Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/696,201	LAI ET AL.	
Examiner	Art Unit	Τ
David Q. Nguyen	2681	

	SEAR	CHED	
Class	Subclass	Date	Examiner
485	416	08/07/05	pw
415	588		
955	415		
455	417	01/11/15	M

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		-	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
search note last search	cefor/to	Ø/
		· · · · · · · · · · · · · · · · · · ·